FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

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| 1875.1040002 | (to be assigned) 10/608,013 (Continuation of U.S. Appl. No. 09/903,502; Filed: July 13, 2001) |
| APPLICANT: Woo, Agnes | |
| FILING DATE (herewith) 6/30/03 | GROUP (to be assigned) 2838 |

**U.S. PATENT DOCUMENTS**

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB-CLASS | FILING DATE |
|---|---|---|---|---|---|---|---|
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| JH | AB1 | 4,385,337 | 05/1983 | Asano *et al.* | 361 | 91 | 06/1981 |
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**FOREIGN PATENT DOCUMENTS**

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUB-CLASS | TRANSLATION |
|---|---|---|---|---|---|---|---|
| JH | AL1 | GB 2 319 893 A | 06/1998 | Great Britain | | | Yes No |
| JH | AM1 | WO 00/21134 | 04/2000 | PCT | | | Yes No |
| | AN1 | | | | | | Yes No |
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| | AP1 | | | | | | Yes No |

**OTHER (Including Author, Title, Date, Pertinent Pages, etc.)**

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| | AS | 1 | Keller, J. K., "Protection of MOS Integrated Circuits from Destruction by Electrostatic Discharge," IIT Research Institute, 1981, pp. 73-80. |
| | AT | 1 | Hulett, T.V., "On Chip Protection of High Density NMOS Devices," pp. 90-96. |

EXAMINER J. Han DATE CONSIDERED 3/30/04

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.